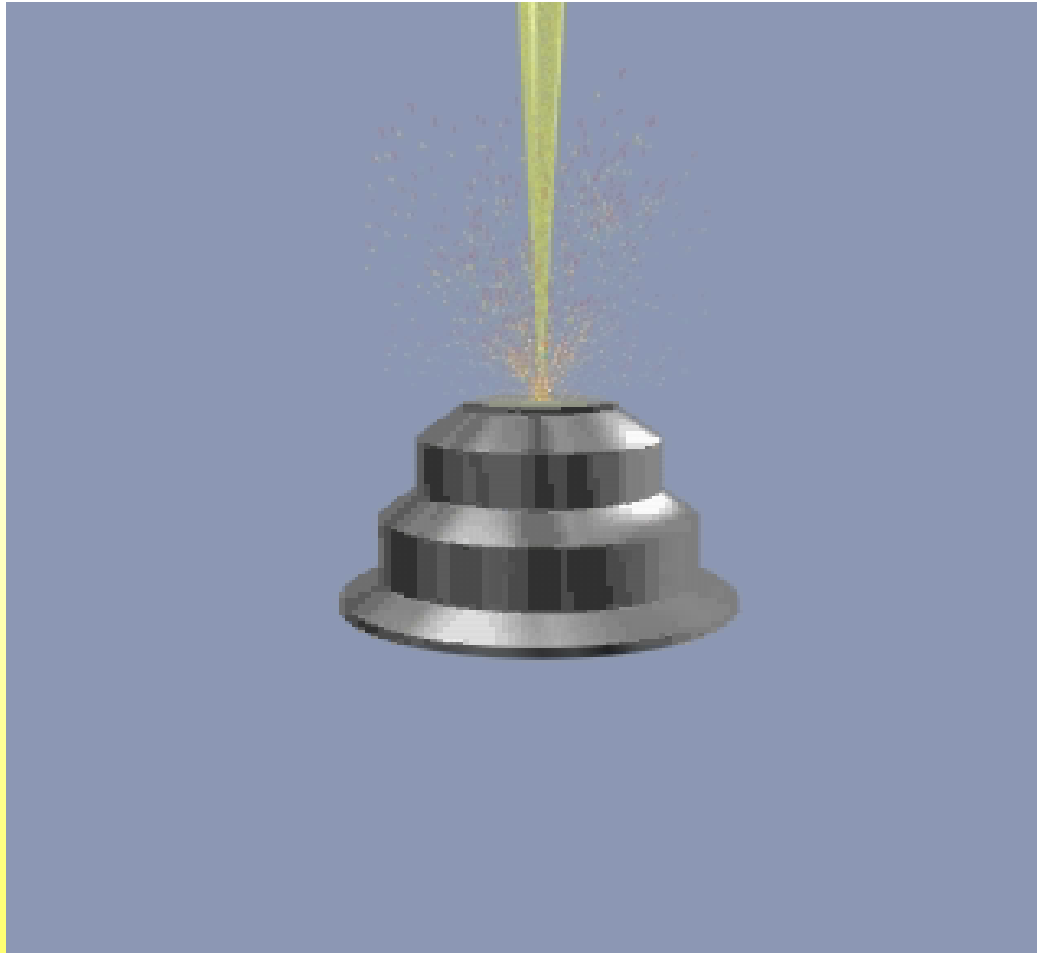


Energy Dispersive Spectrometer (X-rays)

能量分散光譜儀



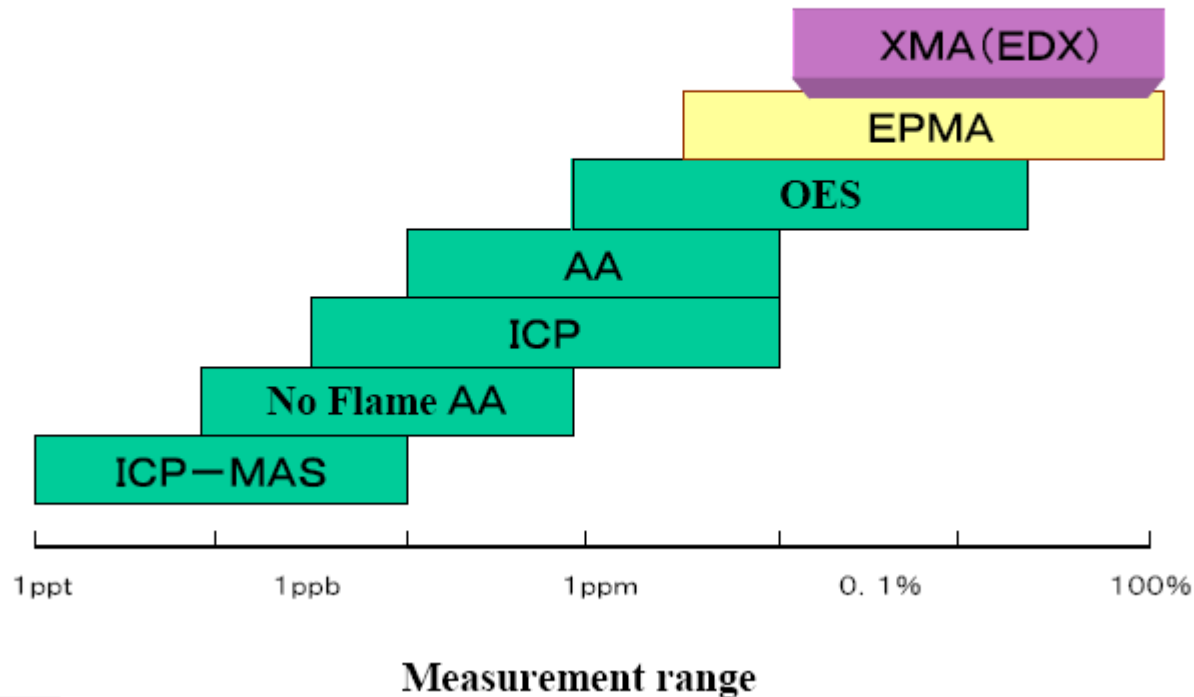
Theory of Energy Dispersive

表面分析技術一般性之比較

分析技術	典型應用	偵測元素	偵測極限	取樣深度	平面解析	影像/成像
AES	Surface Analysis & Depth Profile	Li - U Chemical binding	0.1 ~ 1 at%	5 ~ 50Å	< 10nm	Y SEM/SAM
XPS	Surface Analysis & Depth Profile	Li - U Chemical binding	0.1 ~ 1 at%	5 ~ 75 Å	< 10µm	Y XPS mapping
SEM /EDS	Image & Elemental Microanalysis	B - U (EDS)	0.1 ~ 1 at%	1 ~ 5 µm (EDS)	< 1nm	Y Y
FIB	Cross / thin section, IC Design, Modification	-	-	200 Å	< 5nm	Y
XRD	Phase Identification		< 5%	> 600 Å	5mm	
TXRF	Metal Contamination on Si wafer	S - U	10 E9 ~ E11 at/cm ²	5nm	10mm	Y
RBS	Quantitative Thin Film Composition & Thickness	LI ~ U	10 ⁻¹ - 0.01 - 0.001 at% (Z: 20;70)	20 ~500Å	2mm	Y
SIMS	Dopant & Impurity Depth Profile, Surface, Micro-analysis	H - U	10E12 ~ E16 at/cm ³ (ppm ~ ppb)	50 ~ 300 Å	< 500Å	Y
SPM	Surface Imagine			0.1Å	< 10Å	Y

Theory of Energy Dispersive Spectrometer

Classification of elemental analyzer



Theory of Energy Dispersive

What can you do with EDX analysis

◆ *Qualitative analysis*

• Range : ${}_5\text{Be} \sim {}_{92}\text{U}$

◆ *Quantitative analysis*

• Quantitative analysis by XPP

• Na or more : 0.2~0.3wt% C : about 1wt%

◆ *Mapping (DBC)*

• Multi-element simultaneous mapping

• Line analysis

• Phase analysis

◆ *Particle analysis by elements*

Theory of Energy Dispersive Spectrometer

Pre-treatment sample

Theory of Energy Dispersive

Fixation of a sample (powder)

Sample holder Carbon product (For observation; Aluminum product)

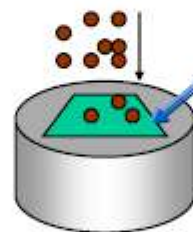
The charge of sample fixed material Carbon tape

For conductive processing Carbon paste Silver paste

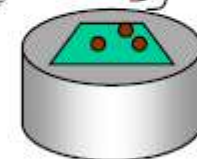


① The spatter method

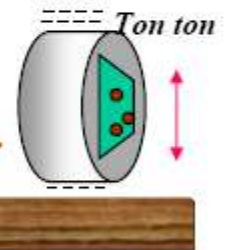
It observes and analyzes in the state.



Carbon tape



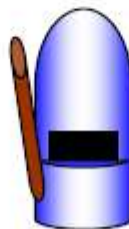
Excessive powder is blown away by blower



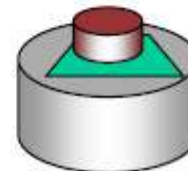
Excessive powder fails to be struck.

② The pressing method

It is suitable for the quantitative analysis.



Press machine



Theory of Energy Dispersive

Fastening sample (massiveness sample)

Sample holder

carbon



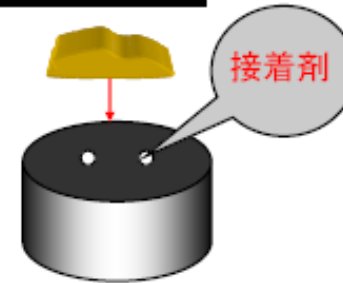
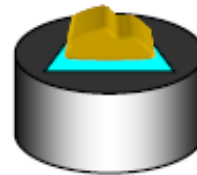
stuck material

carbon tape



① Stuck as it is

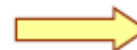
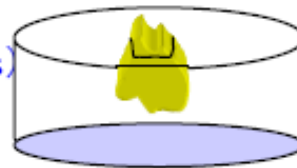
(そのまま観察、分析)



元素マッピングする場合は接着剤で
確実に固定する

② buried in resin

(suitable for quantitative analysis)



試料を樹脂に埋め込む

鏡面研磨する(仕上げはダイヤモンドペースト等)

Theory of Energy Dispersive Spectrometer

Conductive processing of a sample

1. A sample with conductivity

Especially this sample does not need a pretreatment.

However, it is required between a sample and a sample holder to give conductivity at a carbon tape or carbon paste..

2. A sample without conductivity

Carbon coating is performed to this in principle.

Gold and platinum coating are performed to this by the case.

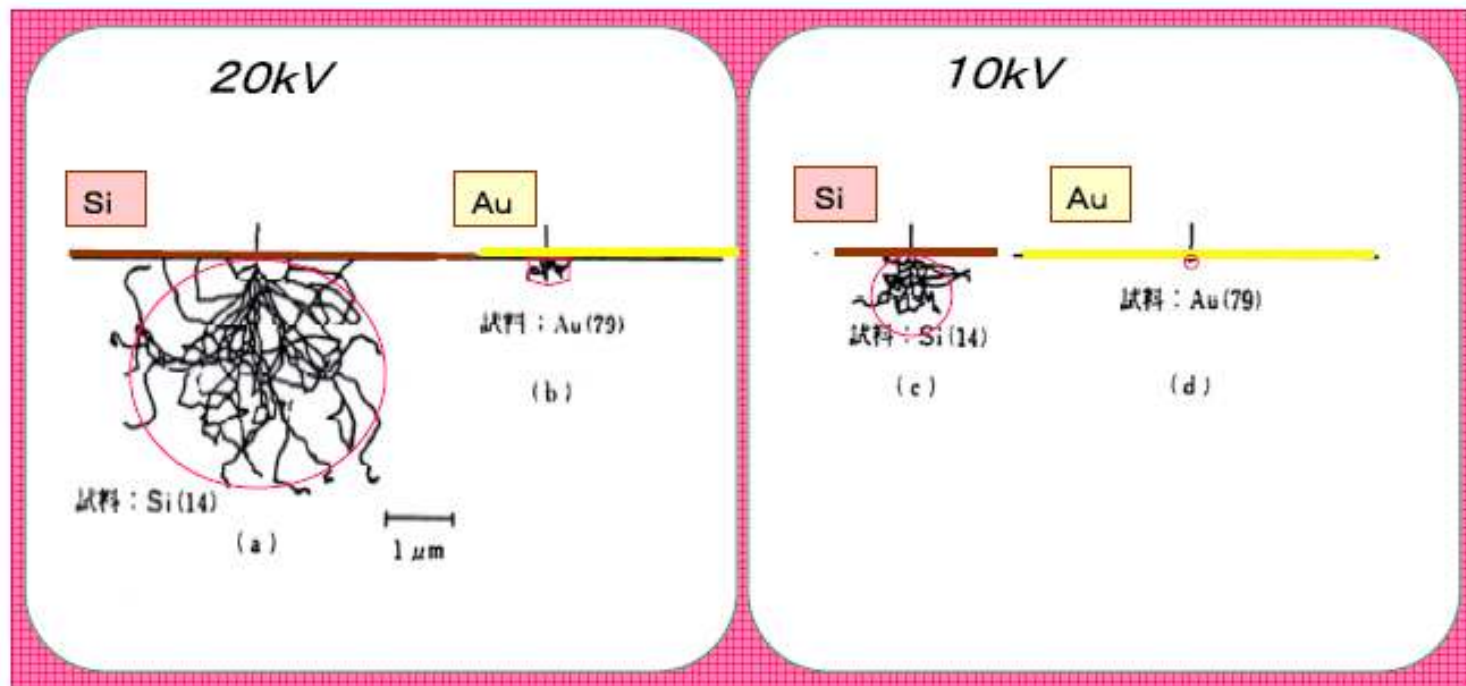
Theory of Energy Dispersive

Influence which the composition element of materials and the accelerating voltage has on the analysis depth

2196—6812—6/40

Although EDX analysis is called surface analysis, the X ray information in several micrometers depth is acquired on the average.

Deeper X ray information is acquired so that accelerating voltage is high, and, so that the average atomic number of a sample becomes low.,



Theory of Energy Dispersive

Coating

2196—6812—19/40

	Au/Pt	C
Image quality	○ Good	△ No Good
分析	△ X rays with small energy are absorbed in the coating layer	○ As for X rays of all energy, absorption in the coating layer is little
	× There are overlap peak	

Theory of Energy Dispersive Spectrometer

Spectrometer

2196—6812—18/40

Carbon, Gold, platinum Coating

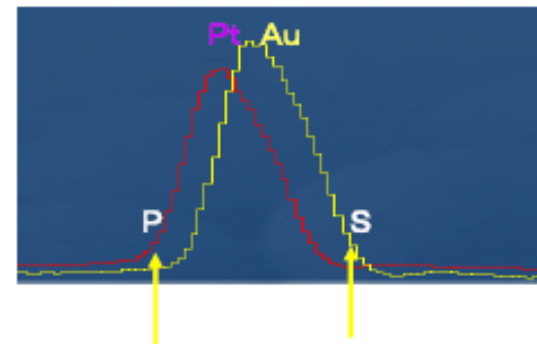
In general, when you observe SEM image, you coat sample with Au, Pt.

But you analyze element.

- ① Characteristic X-ray generated from light elements absorbed by coating layer.
- ② P(phosphorus) and Sulfur peak overlap Gold, Platinum peak.



Carbon Coating



Theory of Energy Dispersive Spectrometer

2196-6812-20/4

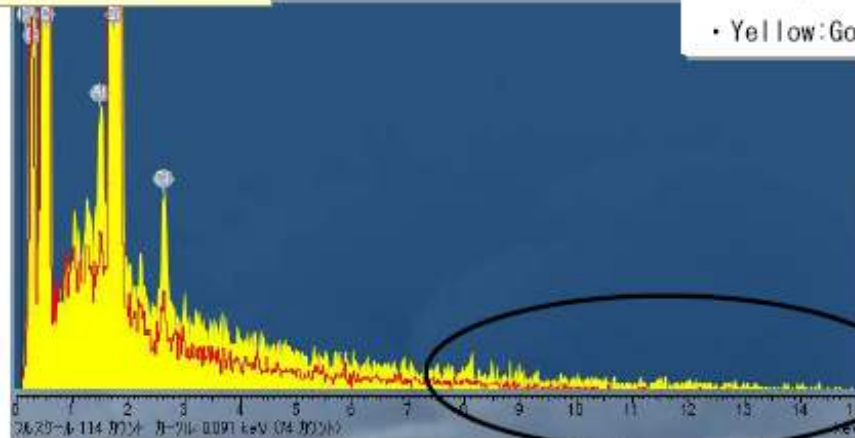
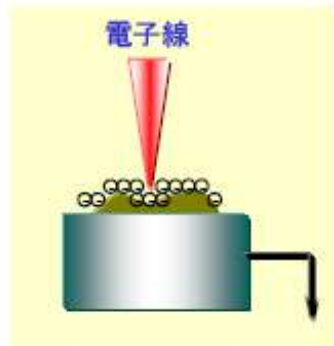
Charge UP

Analysis : Not charge UP !!!

試料：紙

加速電圧：15kV

- Read : Charge UP
- Yellow : Good



SEM像：赤スペクトル
(チャージアップあり)

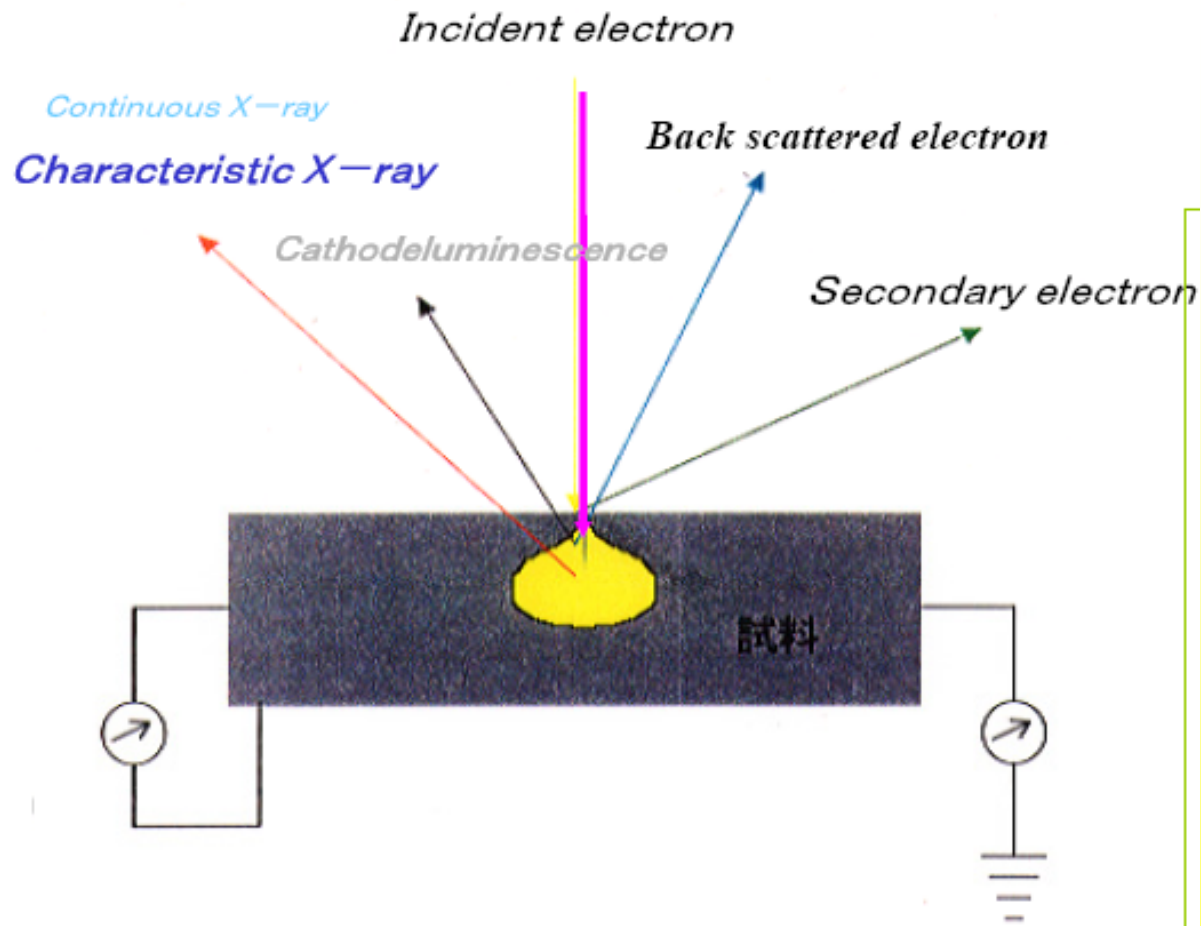
SEM像：黄スペクトル
(チャージアップなし)

Theory of Energy Dispersive Spectrometer

Principle of EDX

Theory of Energy Dispersive Spectrometer

Generation of X-ray



Theory of Energy Dispersive Spectrometer

ELECTRON BEAM

Cathodoluminescence
(Visible light)

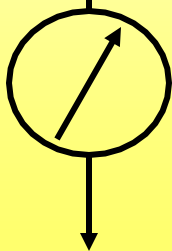
Characteristic
X-rays

Secondary
Electrons

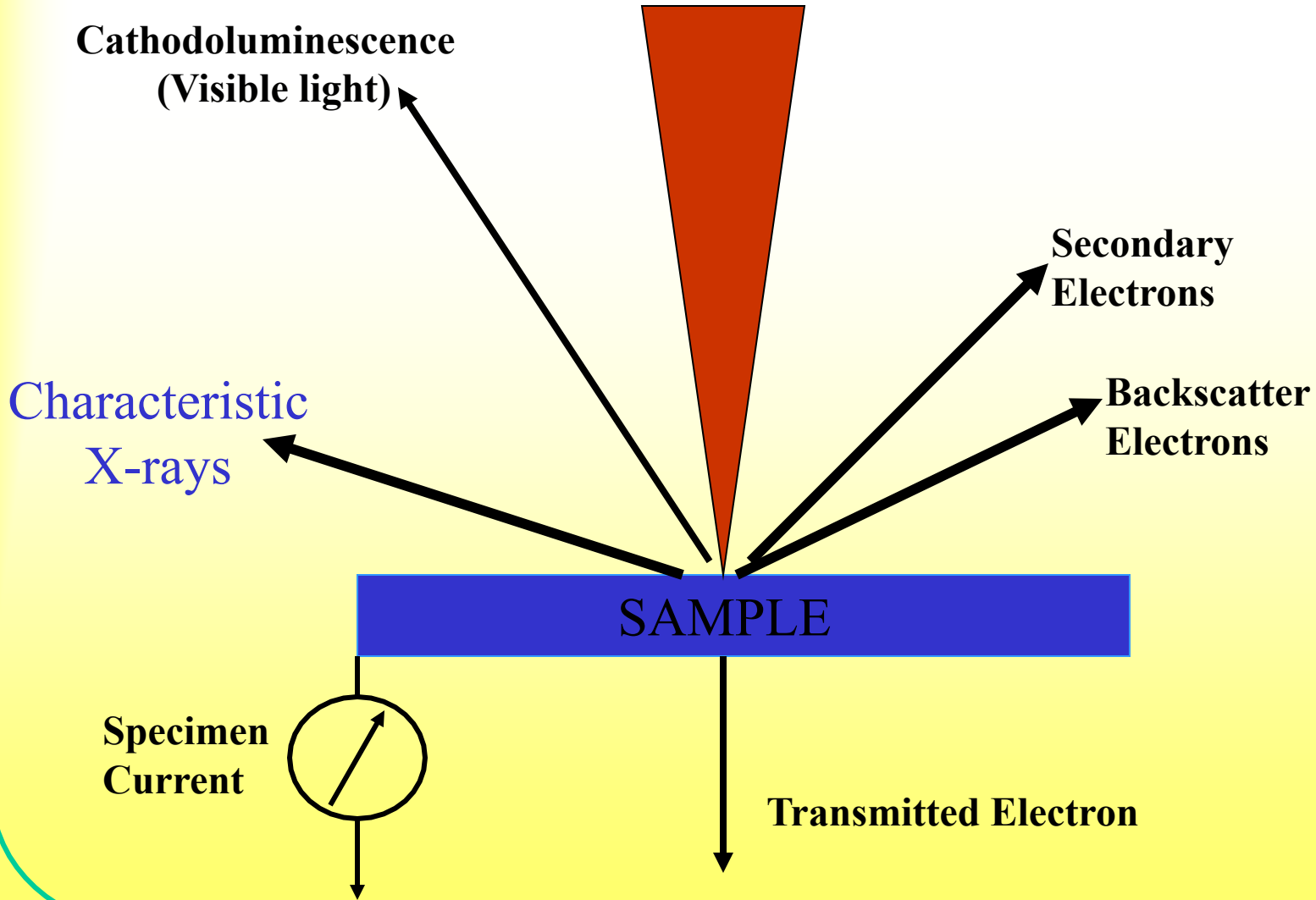
Backscatter
Electrons

SAMPLE

Specimen
Current



Transmitted Electron



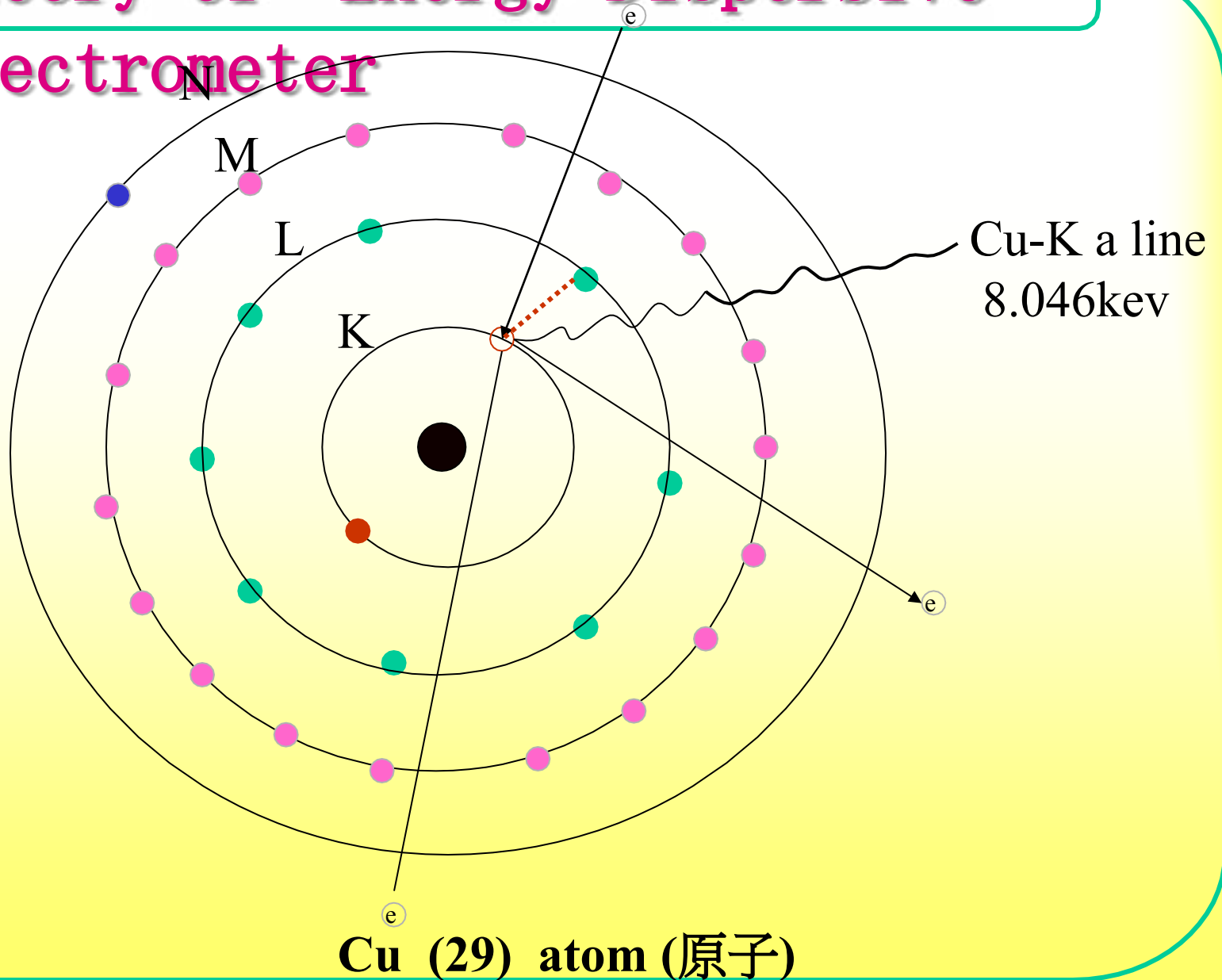
Theory of Energy Dispersive Spectrometer

●特性X-光(Characteristic X-rays)

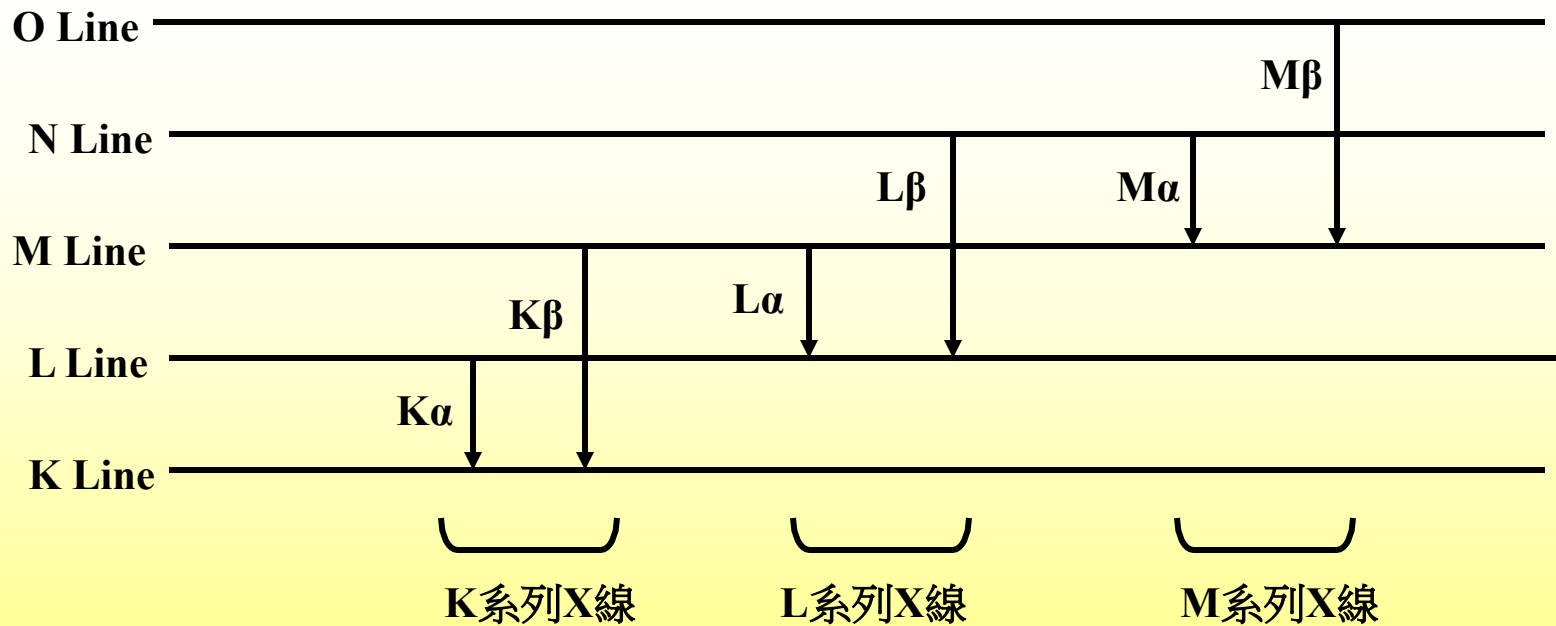
產生機構

1. 電子或X-光激發原子內層電子
2. 外層電子填補空缺
3. 釋放出能量
4. 此能量激發出高階能階電子作為試片元素分析之依據

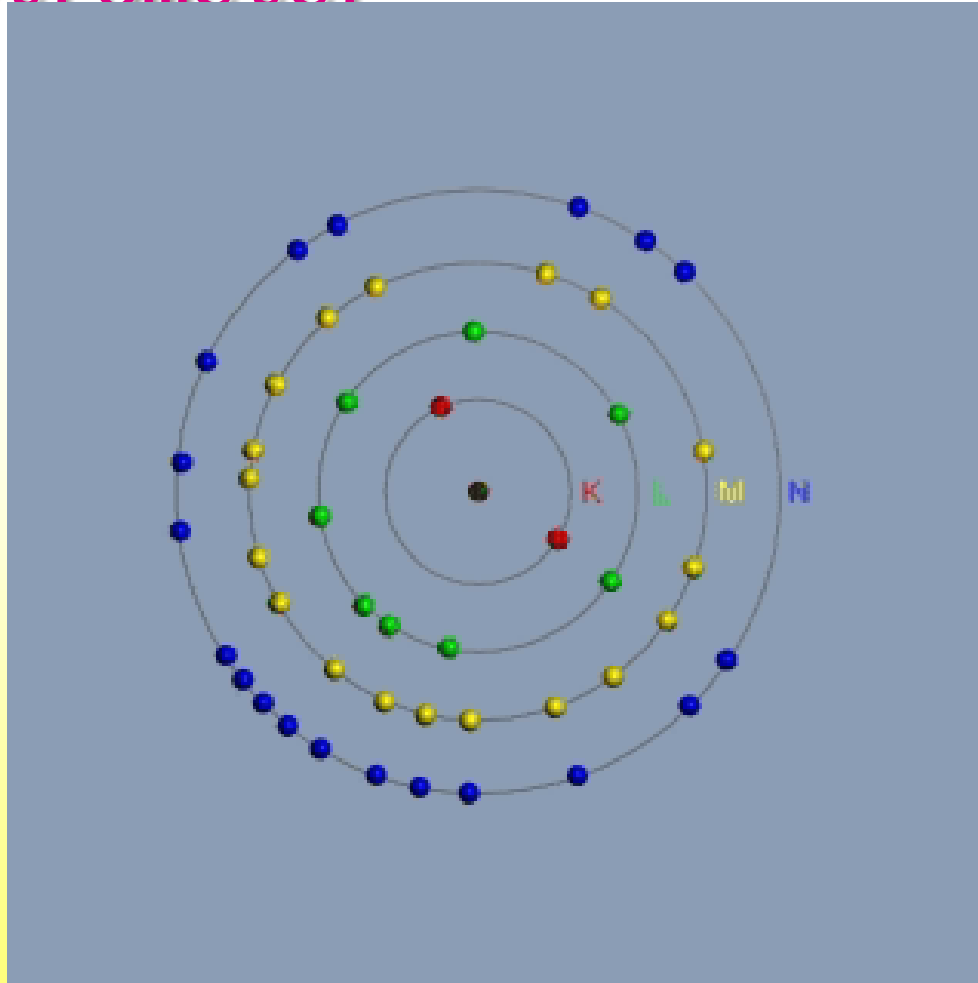
Theory of Energy Dispersive Spectrometer



Theory of Energy Dispersive Spectrometer



Theory of Energy Dispersive Spectrometer



K line energy production

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